

<b>Notic of Ref rences Cited</b>	Application/Control No. 10/028,629	Applicant(s)/Patent Under Reexamination CHAPMAN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6389360	05-2002	Alft et al.	702/9
	B	US-6025851	02-2000	Valdes et al.	345/442
	C	US-6441823	08-2002	Ananya	345/442
	D	US-6111588	08-2000	Newell	345/442
	E	US-5821414	10-1998	Noy et al.	73/152.54
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Derivation of a standard set of geometric constraints for parametric modeling and data exchange", Bettig et al., Computer-Aided Design 33 (2001) 17-33
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.